

VOLTAGE DETECTOR

■ GENERAL DESCRIPTION

The NJU7702/03 is a high precision and low quiescent current voltage detector.

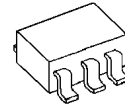
The detection voltage is internally fixed with an accuracy of 1.0%.

The NJU7702/03 are useful for preventing malfunction of microcomputer or DSP etc. through detect a drop in voltage of battery or power supply.

NJU7702 is Nch. Open Drain and NJU7703 is a C-MOS output type.

Small packaging makes NJU7702 and NJU7703 suitable for space conscious applications.

■ PACKAGE OUTLINE



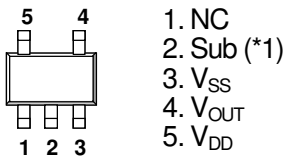
NJU7702/03F

■ FEATURES

- High Precision Detection Voltage $\pm 1.0\%$
- Low Quiescent Current $0.8\mu\text{A typ. (}V_{\text{DET}}=3\text{V version)}$
- Detection Voltage Range $1.3\text{--}6.0\text{V}(0.1\text{V Step)}$
- Output Configuration
 NJU7702: Nch. Open Drain type
 NJU7703: C-MOS Output type
- CMOS Technology
- Package Outline SOT-23-5

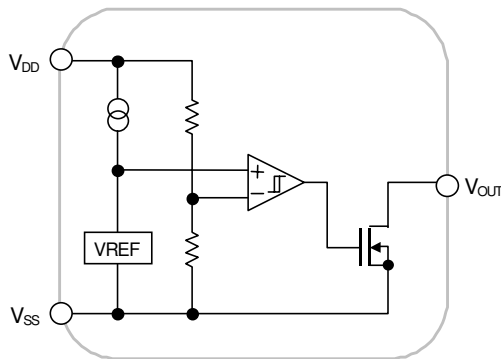
■ PIN CONFIGURATION

NJU7702/03F

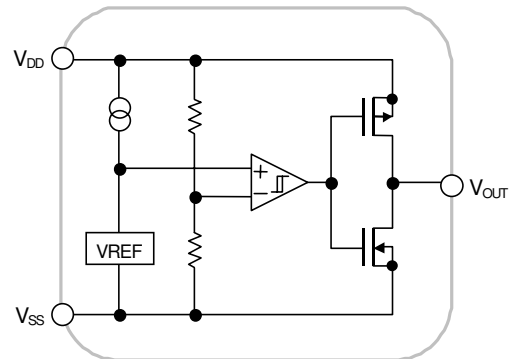


(*1): Connect Sub terminal to GND.

■ EQUIVALENT CIRCUIT



NJU7702



NJU7703

NJU7702/03

■ DETECTION VOLTAGE RANK LIST

3Device Name	V _{DET}
NJU7702/03F13	1.3V
NJU7702/03F27	2.7V
NJU7702/03F28	2.8V
NJU7702/03F03	3.0V
NJU7702/03F31	3.1V
NJU7702/03F42	4.2V
NJU7702/03F06	6.0V

■ NJU7702

■ ABSOLUTE MAXIMUM RATINGS (Ta=25°C)

PARAMETER	SYMBOL	RATINGS	UNIT
Input Voltage	V _{DD}	+10	V
Output Voltage	V _{OUT}	V _{SS} -0.3~+10	V
Output Current	I _{OUT}	50	mA
Power Dissipation	P _D	200(*2)	mW
Operating Temperature	T _{opr}	-40 ~ +85	°C
Storage Temperature	T _{stg}	-40 ~ +125	°C

(*2) : Device itself

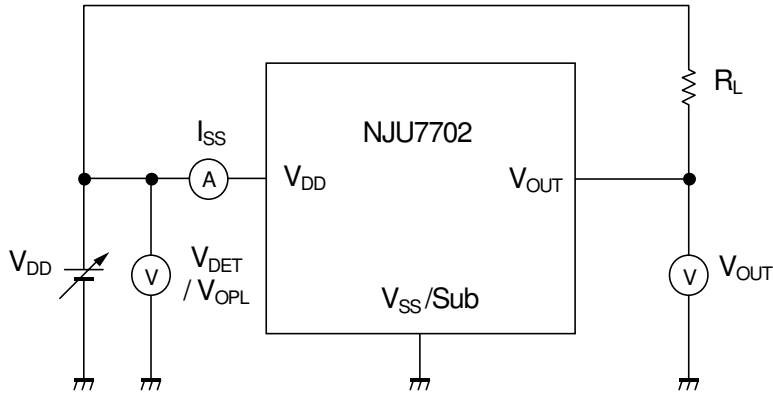
■ ELECTRICAL CHARACTERISTICS (Ta=25°C)

PARAMETER	SYMBOL	TEST CONDITION	MIN.	TYP.	MAX.	UNIT	
Detection Voltage	V _{DET}		-1.0%	-	+1.0%	V	
Hysteresis Voltage	V _{HYS}		V _{DET} ×0.03	V _{DET} ×0.05	V _{DET} ×0.08	V	
Quiescent Current	I _{SS}	V _{DD} =V _{DET} +1V	V _{DET} =1.3V~1.7V Version	-	0.5	1.0	μA
			V _{DET} =1.8V~6.0V Version	-	0.8	1.6	μA
Output Current	I _{OUT}	Nch, V _{DS} =0.5V	V _{DD} =1.2V	0.75	2.0	-	mA
			V _{DD} =2.4V (≥2.7V Version)	4.5	7.0	-	mA
Output Leak Current	I _{LEAK}	V _{DD} =V _{OUT} =9V	-	-	0.1	μA	
Detection Voltage Temperature Coefficient	Δ V _{DET} / ΔTa	Ta=0 ~ +85°C	-	±100	-	ppm/°C	
Operating Voltage (*3)	V _{DD}	R _L =100kΩ	0.8	-	9	V	

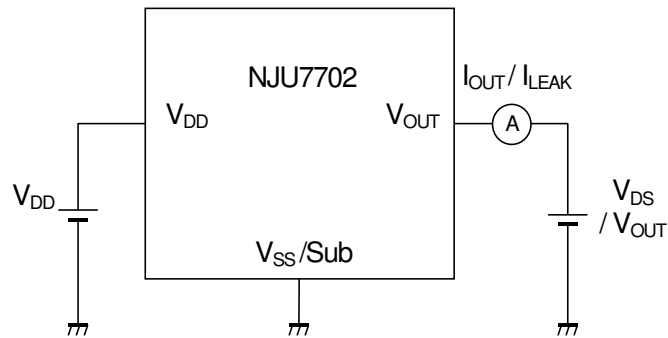
(*3): The minimum Operating Voltage(V_{OPL}) indicates the same value of the input voltage(V_{DD}) on condition that V_{OUT} becomes 10% or less of the input voltage(V_{DD}).

■ TEST CIRCUIT

① COMMON TEST CIRCUIT



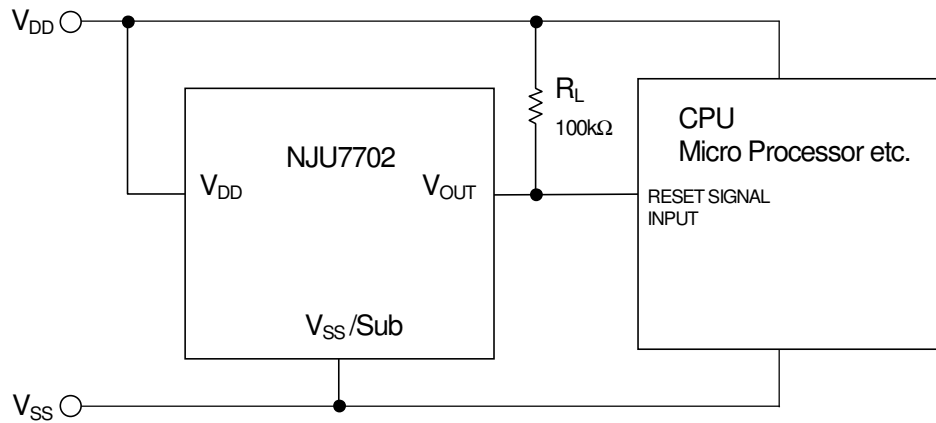
② OUTPUT CURRENT/OUTPUT LEAK CURRENT TEST CIRCUIT



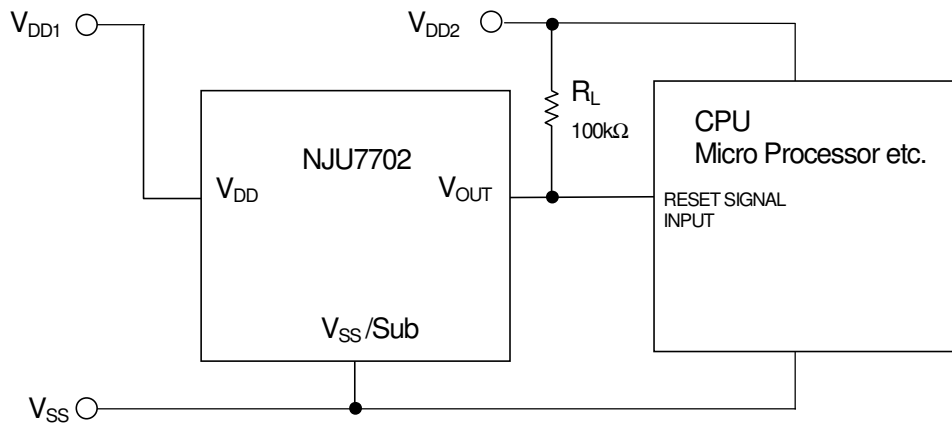
NJU7702/03

■ TYPICAL APPLICATION

① In case of using one power supply.



② In case of using two power supply.



■ NJU7703

■ ABSOLUTE MAXIMUM RATINGS (Ta=25°C)

PARAMETER	SYMBOL	RATINGS	UNIT
Input Voltage	V_{DD}	+10	V
Output Voltage	V_{OUT}	$V_{SS}-0.3 \sim V_{DD}+0.3$	V
Output Current	I_{OUT}	50	mA
Power Dissipation	P_D	200(*4)	mW
Operating Temperature	T_{opr}	-40 ~ +85	°C
Storage Temperature	T_{stg}	-40 ~ +125	°C

(*4) : Device itself

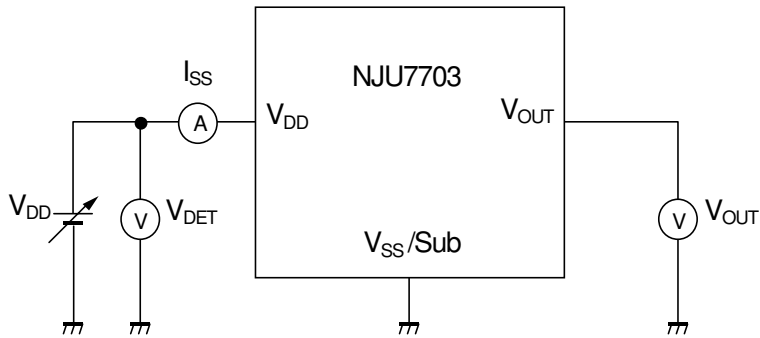
■ ELECTRICAL CHARACTERISTICS (Ta=25°C)

PARAMETER	SYMBOL	TEST CONDITION	MIN.	TYP.	MAX.	UNIT	
Detection Voltage	V_{DET}		-1.0%	-	+1.0%	V	
Hysteresis Voltage	V_{HYS}		$V_{DET} \times 0.03$	$V_{DET} \times 0.05$	$V_{DET} \times 0.08$	V	
Quiescent Current	I_{SS}	$V_{DD}=V_{DET}+1V$	$V_{DET}=1.3V \sim 1.7V$ Version	-	0.5	1.0	μA
			$V_{DET}=1.8V \sim 6.0V$ Version	-	0.8	1.6	μA
Output Current	I_{OUT}	Nch, $V_{DS}=0.5V$	$V_{DD}=1.2V$	0.75	2.0	-	mA
			$V_{DD}=2.4V$ ($\geq 2.7V$ Version)	4.5	7.0	-	mA
			$V_{DD}=4.8V$ ($\leq 3.9V$ Version)	2.0	3.5	-	mA
		Pch, $V_{DS}=0.5V$	$V_{DD}=6.0V$ (4.0V~5.6V Version)	2.5	4.0	-	mA
			$V_{DD}=8.4V$ ($\geq 5.7V$ Version)	3.0	5.0	-	mA
Detection Voltage Temperature Coefficient	$\Delta V_{DET} / \Delta Ta$	$Ta=0 \sim +85^\circ C$	-	± 100	-	ppm/°C	
Operating Voltage (*5)	V_{DD}	$R_L=100k\Omega$	0.8	-	9	V	

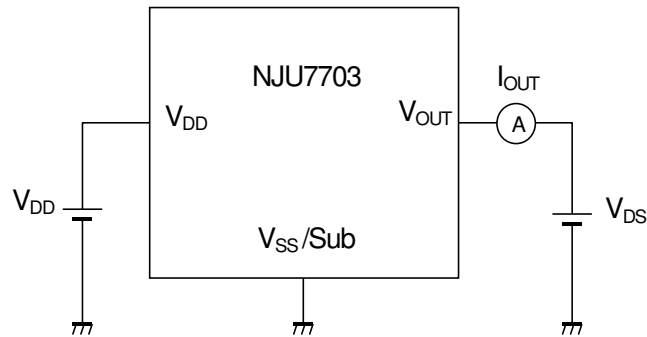
(*5): The minimum Operating Voltage(V_{OPL}) indicates the same value of the input voltage(V_{DD}) on condition that V_{OUT} becomes 10% or less of the input voltage(V_{DD}).

■ TEST CIRCUIT

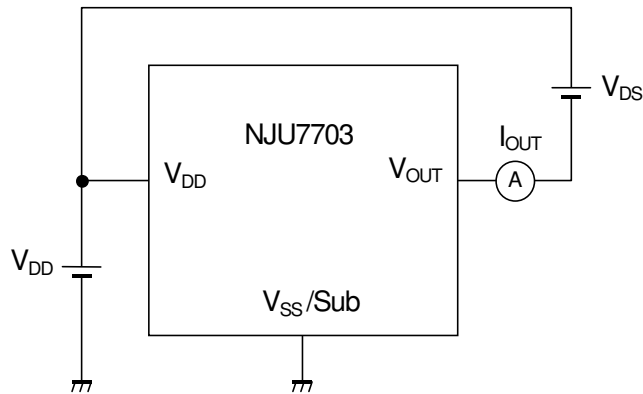
① COMMON TEST CIRCUIT



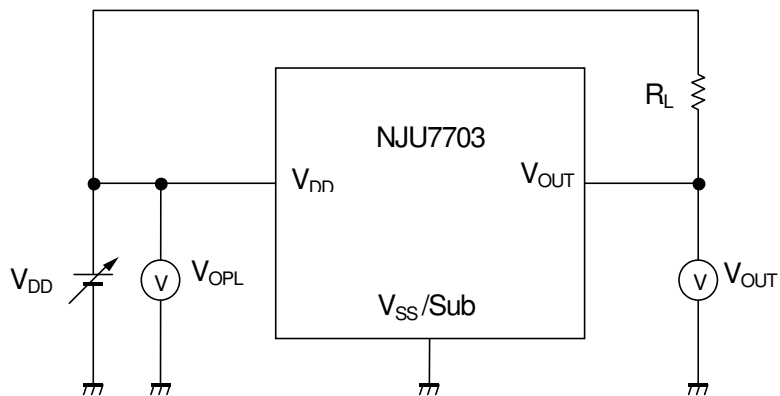
② Nch OUTPUT CURRENT TEST CIRCUIT



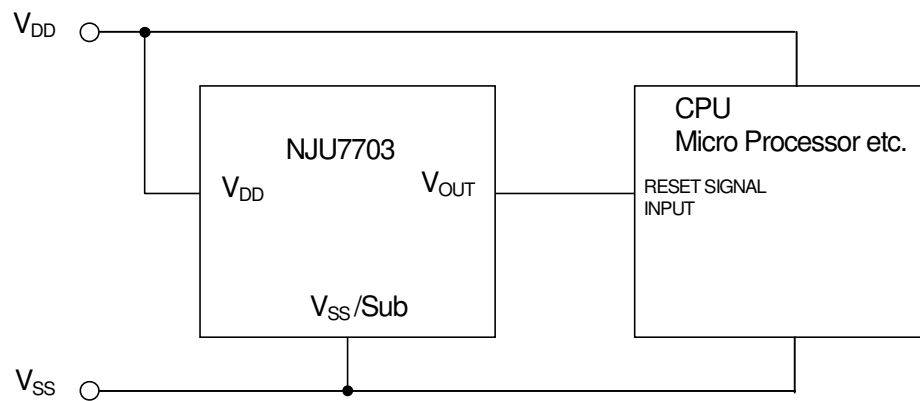
③ Pch OUTPUT CURRENT TEST CIRCUIT



④ MINIMUM OPERATING VOLTAGE TEST CIRCUIT

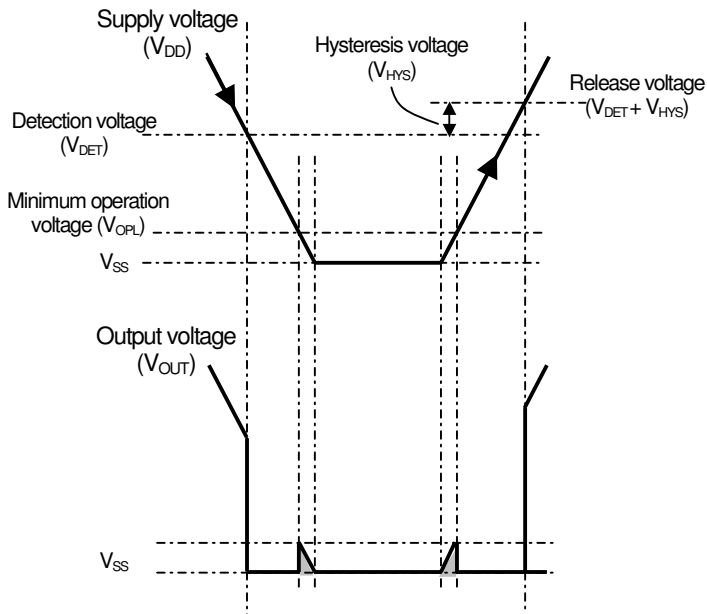


■ TYPICAL APPLICATION



FUNCTIONAL DESCRIPTION

(1) Basic operation



- (1) When supply voltage (V_{DD}) drops below detection voltage (V_{DET}), Output voltage (V_{OUT}) changes "H" to "L" to alert reset state.
- (2) The reset state is kept while V_{DD} is lower than release voltage. The release voltage is a sum of V_{DET} and Hysterisis voltage (V_{HYS}). Please refer to the (*7) below.
- (3) When V_{DD} becomes higher than the release voltage, then V_{OUT} changes from "L" to "H" to resume normal state.

(*7) V_{HYS} is to avoid unstable V_{OUT} state caused by rapid voltage change at nearby V_{DET} .

(*8): C-MOS output product (NJU7703) : When V_{DD} less than V_{OPL} , V_{OUT} is free of the shaded region.

[CAUTION]

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